Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/748,152	LEE ET AL.	
Examiner	Art Unit	
Yonel Beaulieu	3661	

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Class	Subclass	Date	Examiner
701	41-44	11/19/2005	YB
180	6.2	11/19/2005	YB
	443		
280	5.51	11/20/2005	YB

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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DATE	EXMR
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